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# Radiation at Mars with SRAM- Based Monitors

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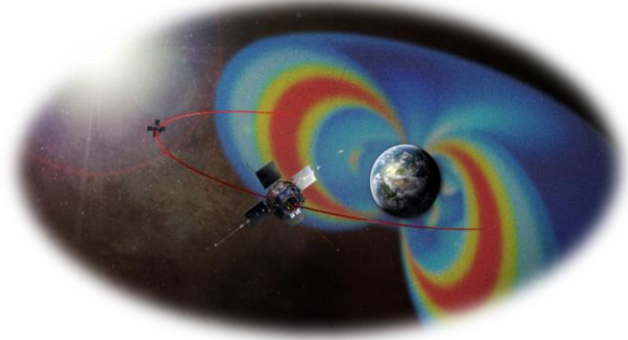


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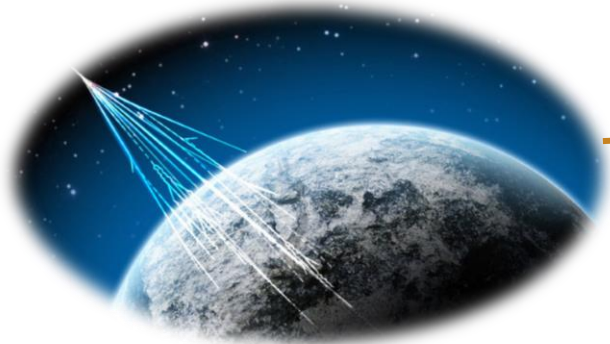
# Space Radiation Environment

Van Allen Radiation Belts



Protons and electrons

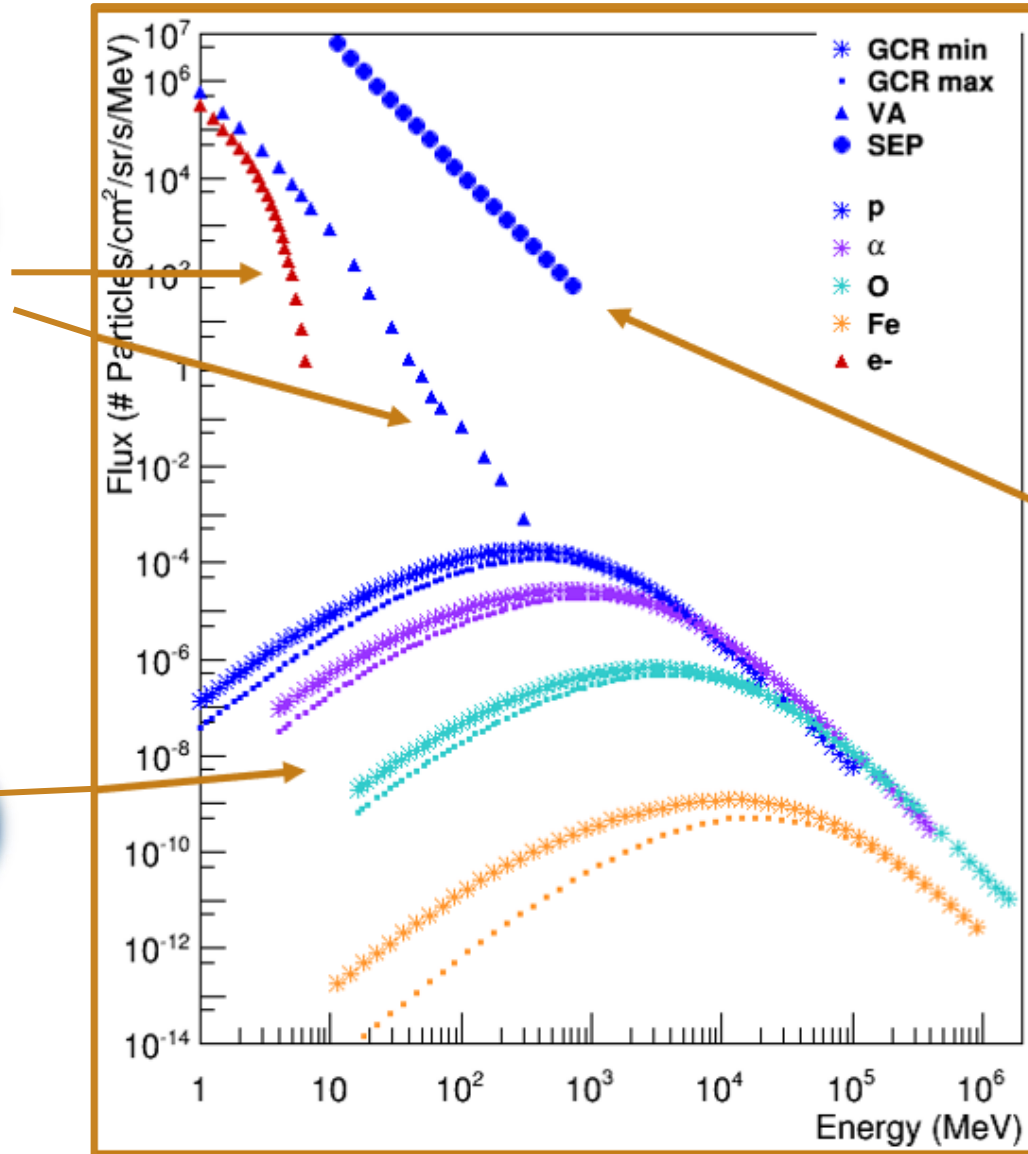
Galactic Cosmic Radiation



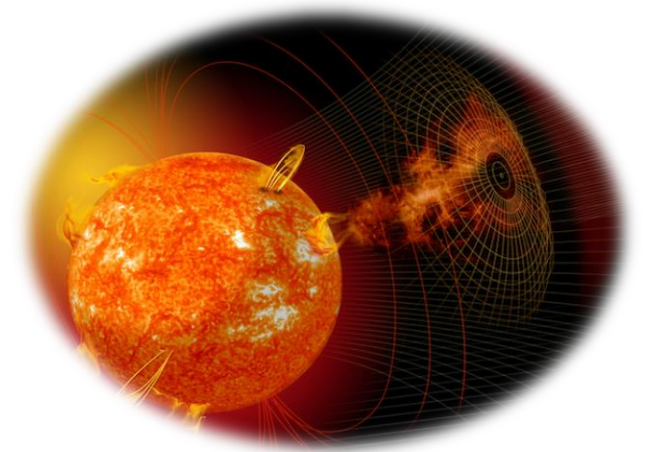
Mainly protons and  $\alpha$  particles

Solar min: 2009

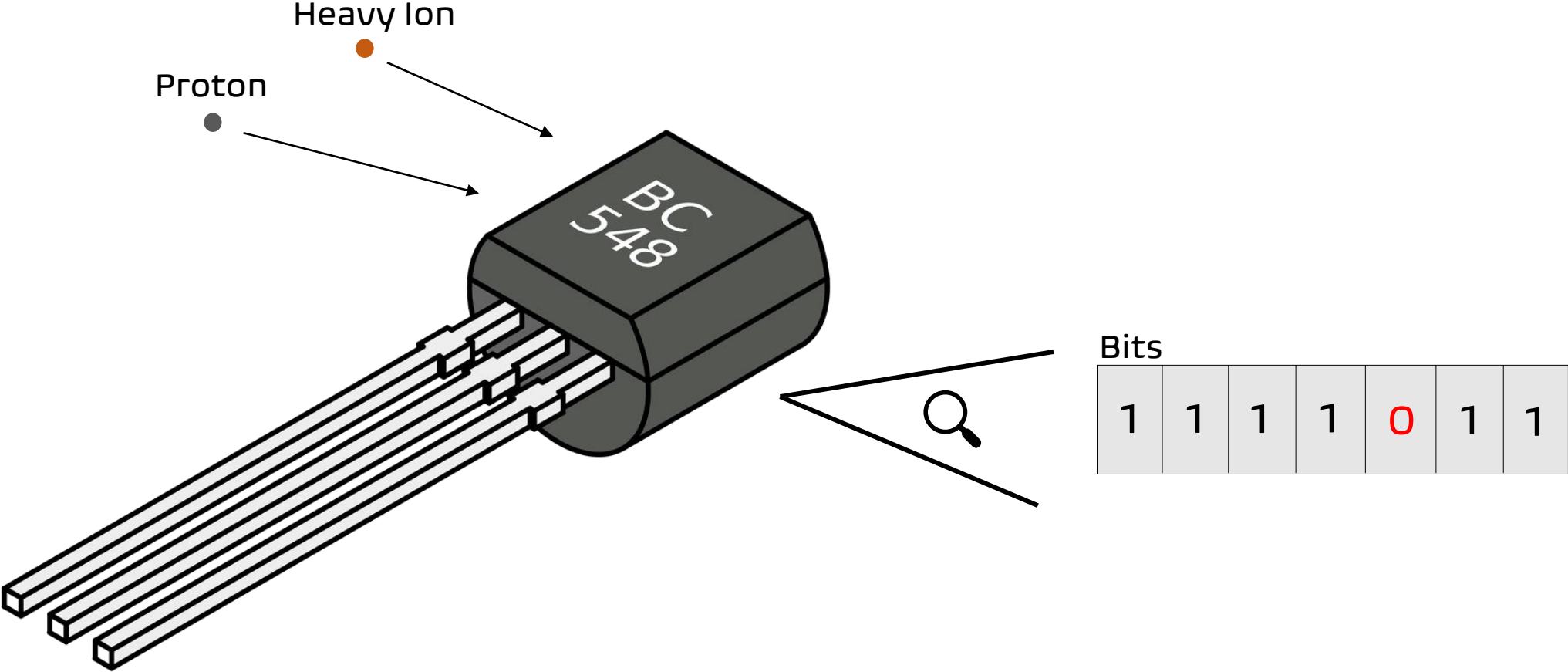
Solar max: 2014



Solar Energetic Particle (SEP) Events



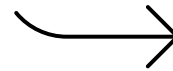
Protons  
Integrated 14 day SEP  
event of December 2006



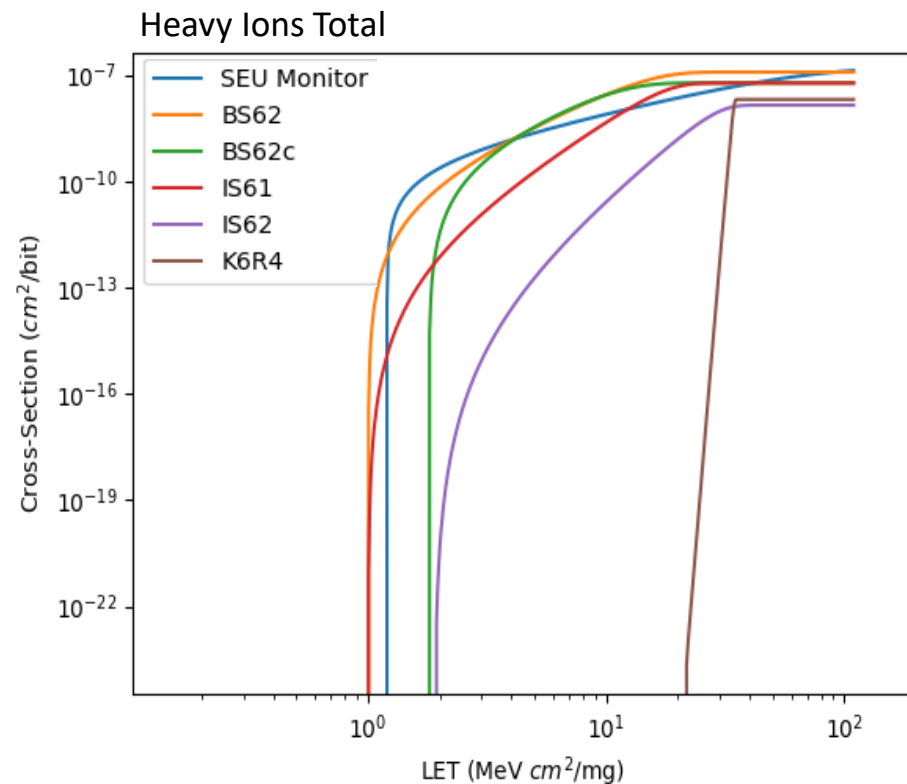
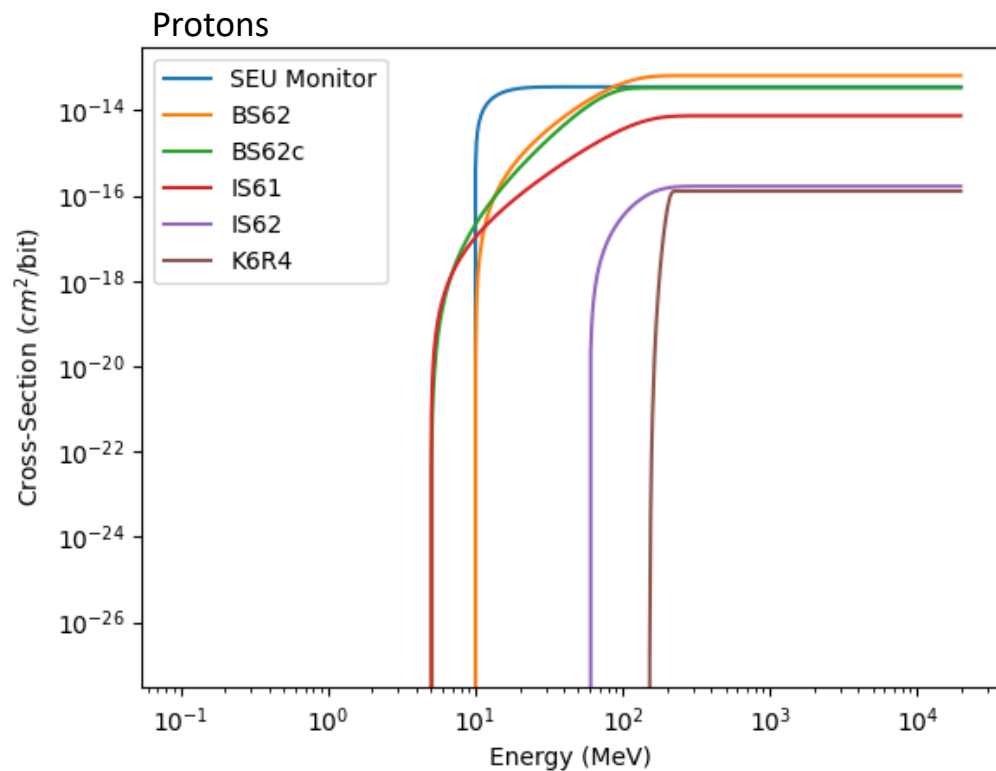
How did we predict the upsets on these devices?



Weibull function parameters



Cross-Section



Protons:

$$N = \int_{E_{min}}^{E_{max}} \frac{d\Phi}{dE}(E) \cdot \sigma_{nucleon}(E) dE$$

- Particle spectrum
- Weibull Curve

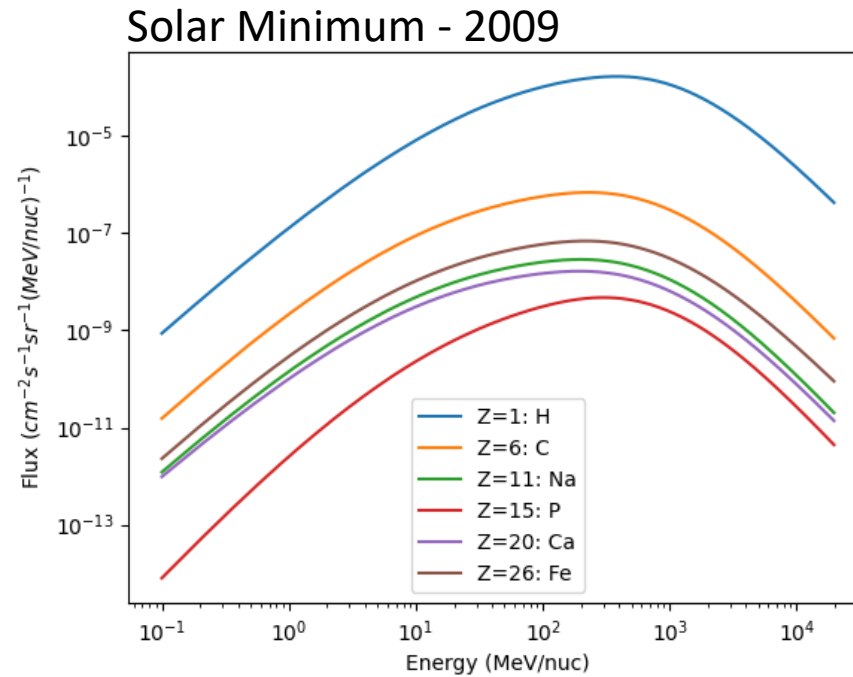
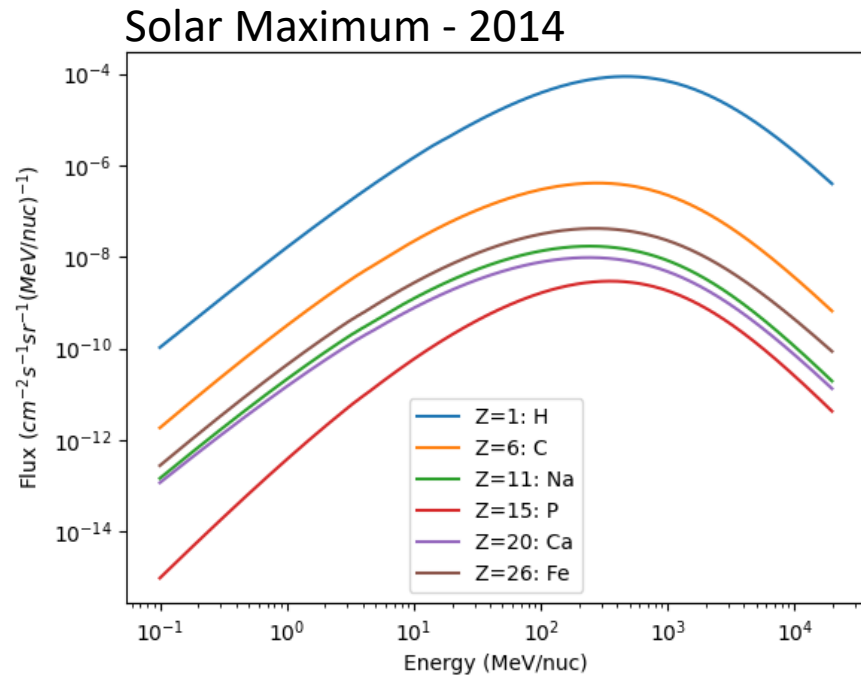
Heavy Ions:

$$N_{RPP} = \frac{A E_c}{4 \rho} \int_{LET_{Min}}^{LET_{Max}} \frac{1}{LET^2} \cdot \Phi(>LET) \cdot \frac{dP_{CL}}{dD(LET)} D(LET) \cdot dLET$$

$$N_{IRPP} = \int_{LET_i,Min}^{LET_i,Max} \frac{d\sigma_{ion}}{dLET}(LET_i) \cdot N_{RPP}(LET_i) dLET_i$$

# Element abundance effect on Galactic Cosmic Rays flux

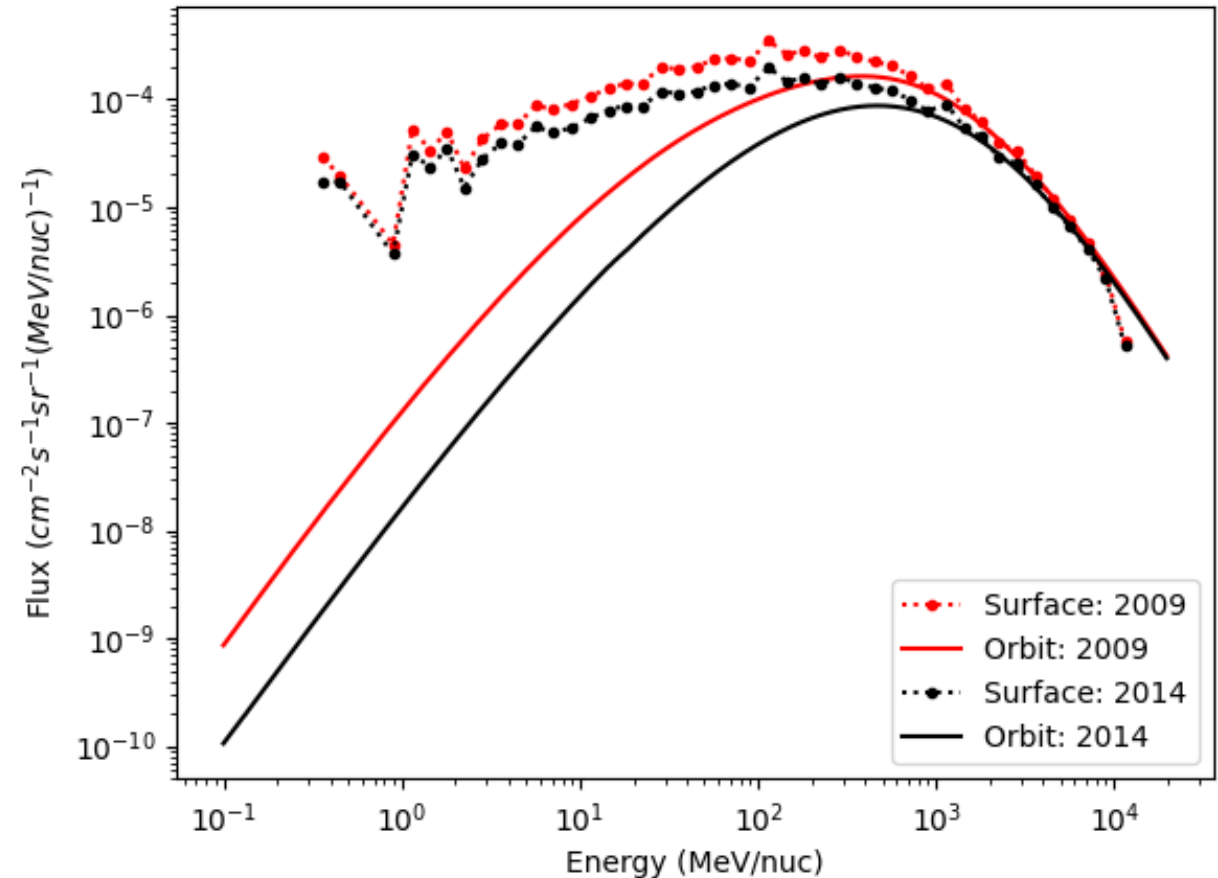
- The fluxes data was obtained using the ISO standard 15390 model, which relies on the number of sun spots detected at Geostationary orbit



X	Atomic Number (Z)	[X]/[H]
H	1	1.000E+00
He	2	8.140E-02
Li	3	9.753E-05
Be	4	4.383E-05
B	5	2.157E-04
C	6	1.671E-03
N	7	2.444E-04
O	8	1.570E-03
F	9	5.123E-06
Ne	10	1.507E-04
Na	11	1.784E-05
Mg	12	2.264E-04
Al	13	3.302E-05
Si	14	1.898E-04
P	15	3.036E-06
S	16	2.087E-05
Cl	17	1.898E-06
Ar	18	4.554E-06
K	19	2.657E-06
Ca	20	1.195E-05
Sc	21	1.898E-06
Ti	22	1.101E-05
V	23	5.123E-06
Cr	24	1.374E-05
Mn	25	5.693E-06
Fe	26	1.152E-04
Co	27	6.519E-07
Ni	28	6.452E-06

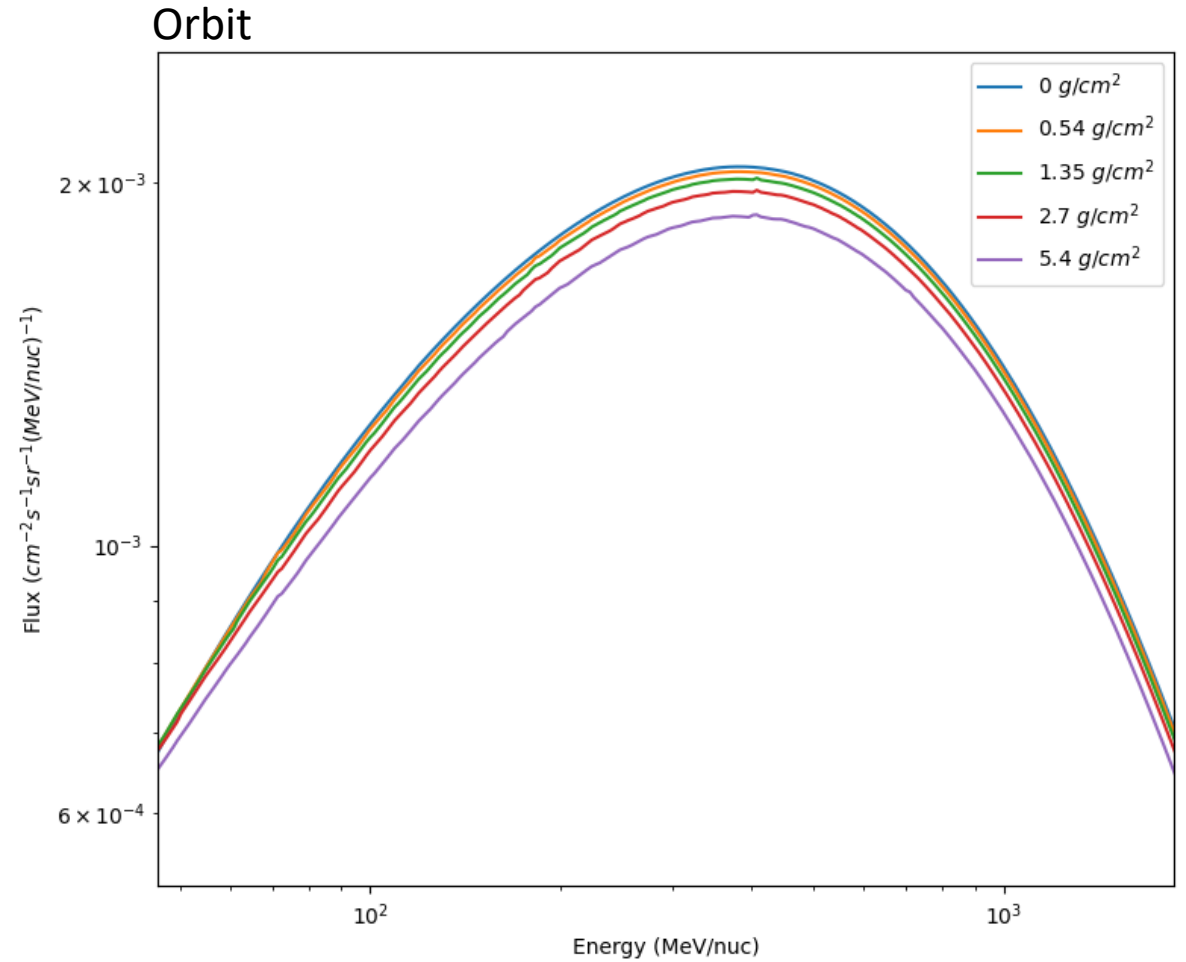
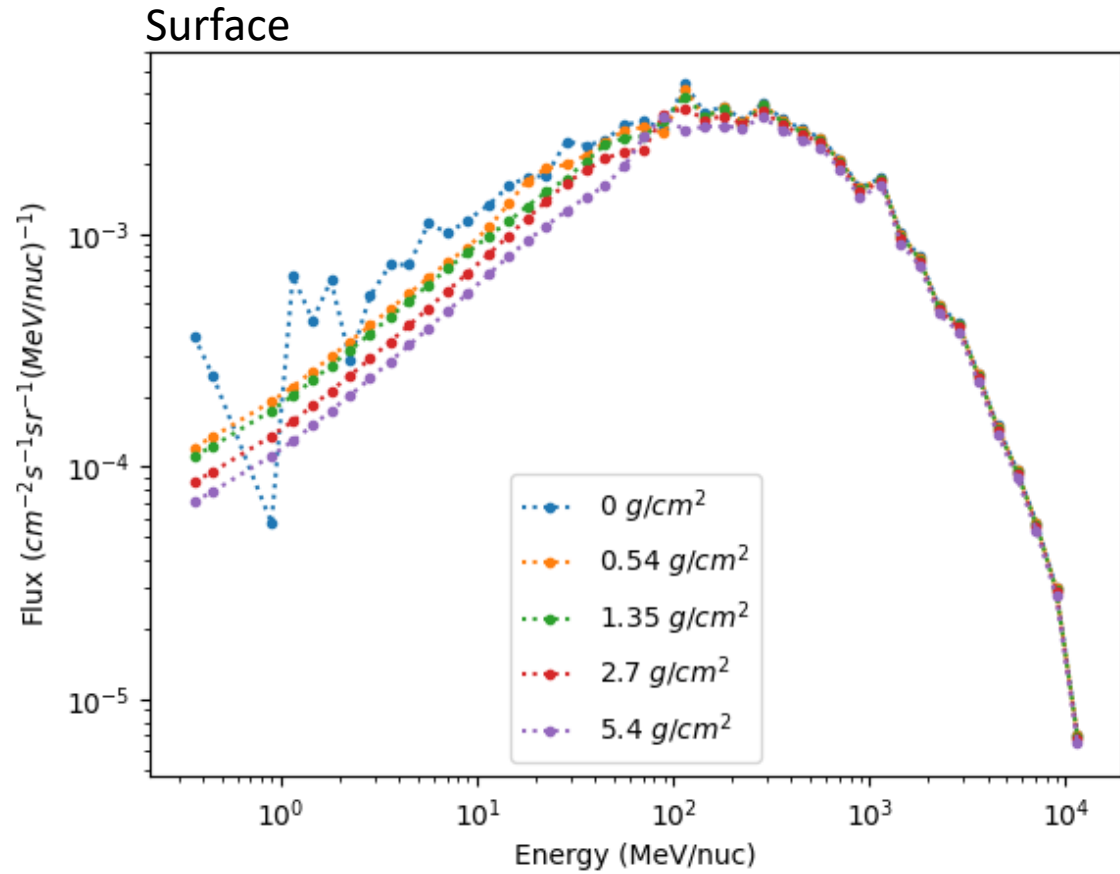
# Proton flux for Solar minimum (2009) and maximum (2014) at the Surface of Mars

- The fluxes data for the surface of Mars was produced with the detailed Martian Energetic Radiation Environment Model (**dMEREM**) developed by LIP for the European Space Agency (ESA);
- This model does a martian atmosphere propagation of particles;
- The atmosphere of Mars was estimated to have a density of **20 g/cm<sup>2</sup>**.





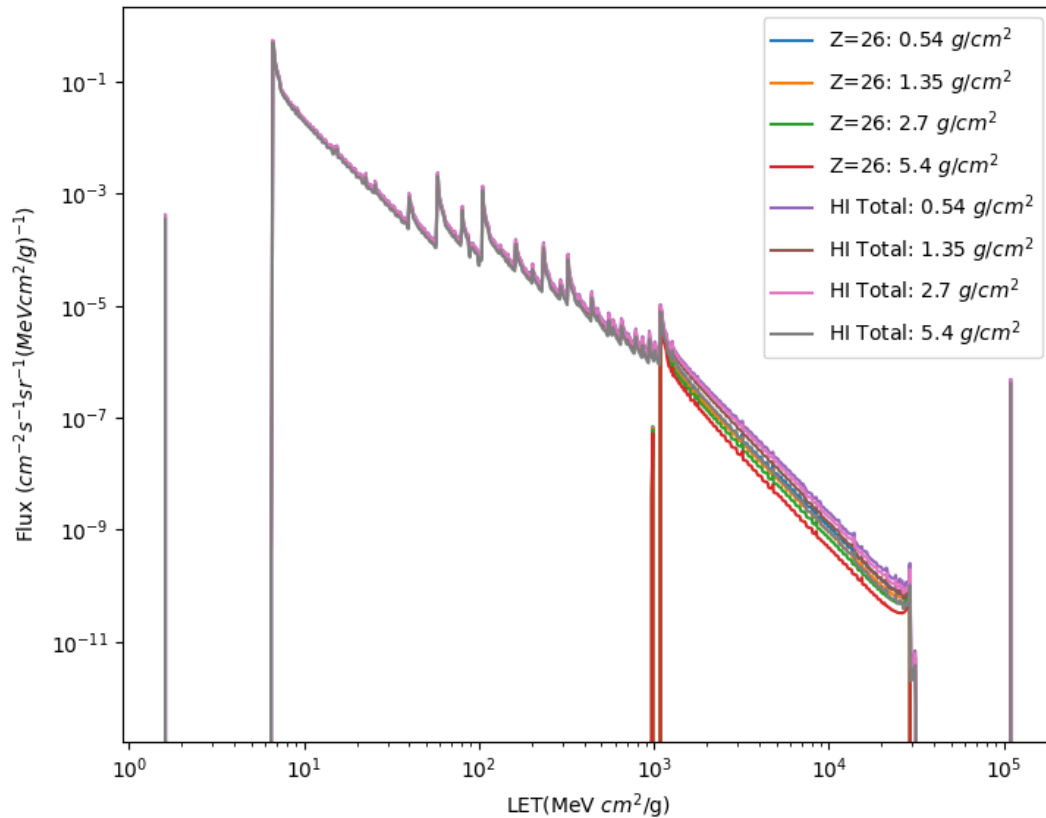
# Aluminium Shielding Effect on Proton flux for Solar minimum (2009)



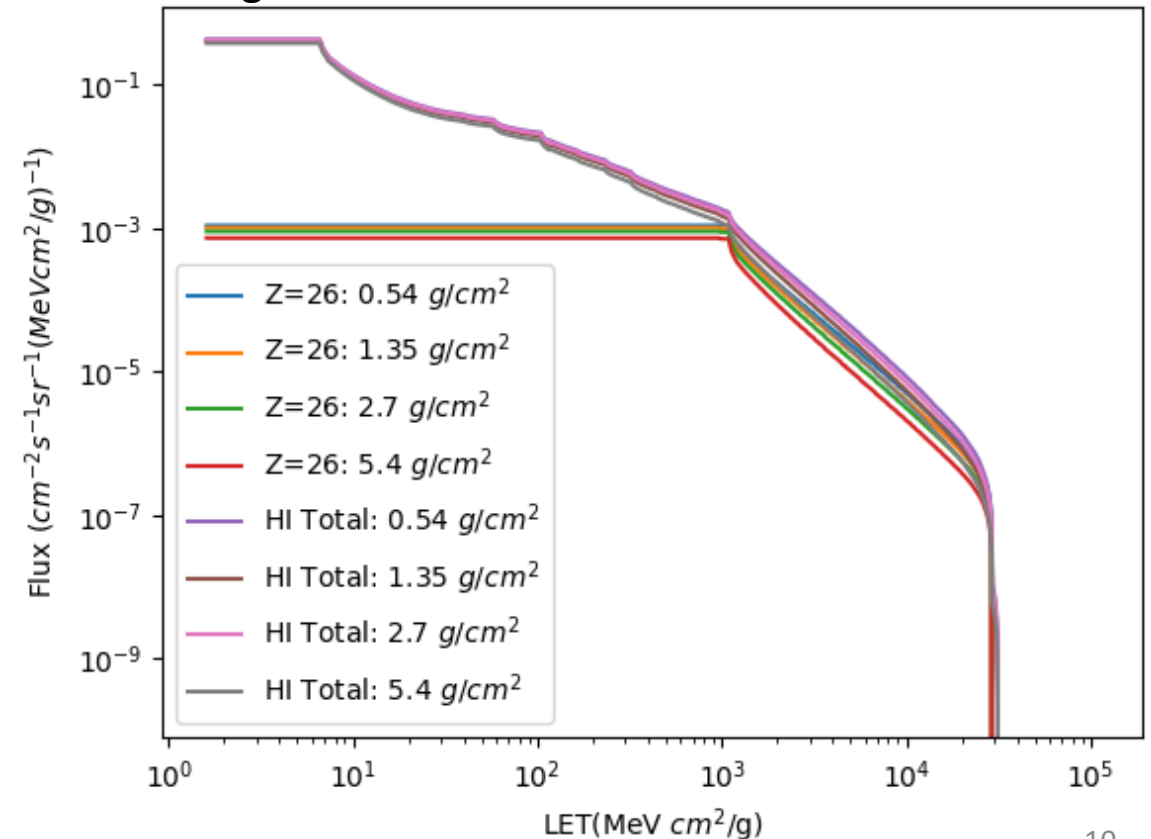
# Shielding Effect at Orbit for Iron and Total Heavy Ions fluxes in LET

- The **Stopping Powers** are in relation to **silicon**;
- Stopping Powers depend on the type of shielding material considered.

Differential Fluxes at 2009

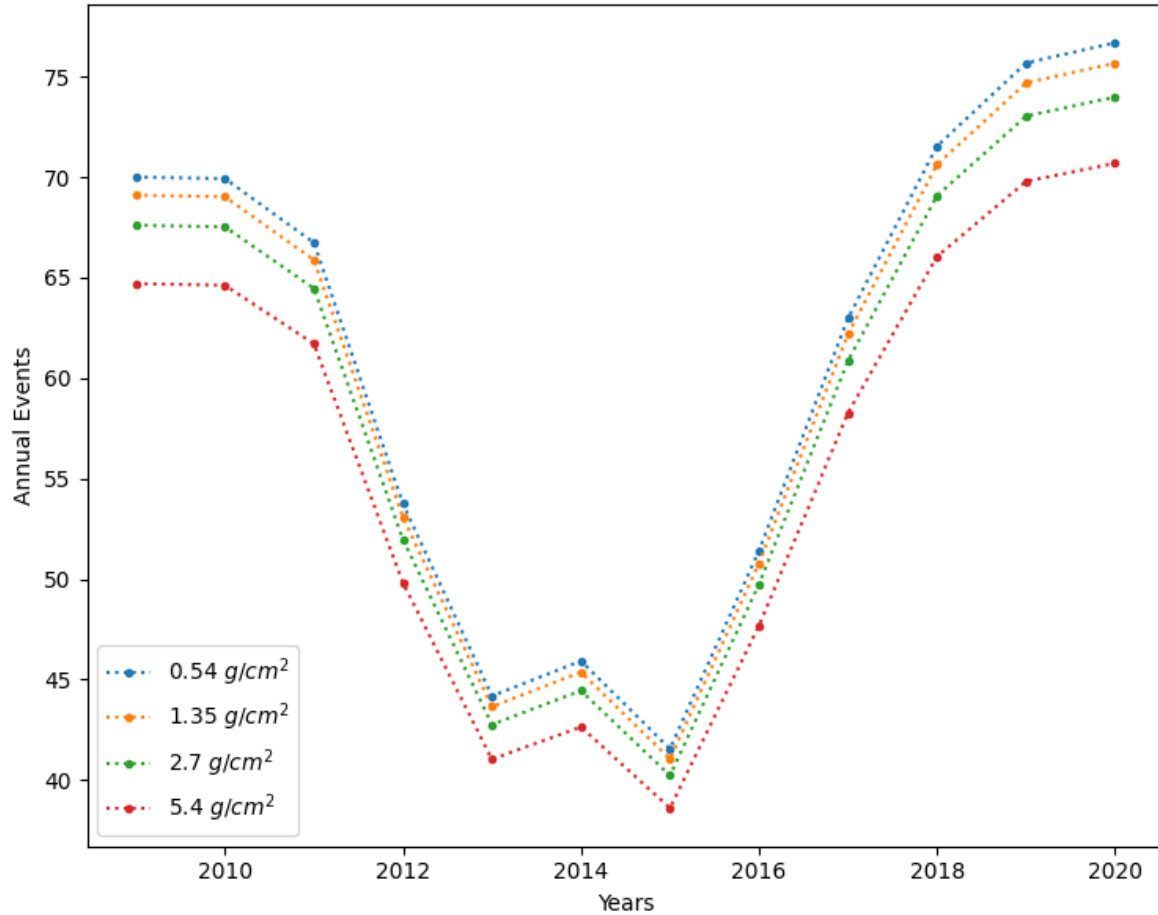


Integral Flux at 2009

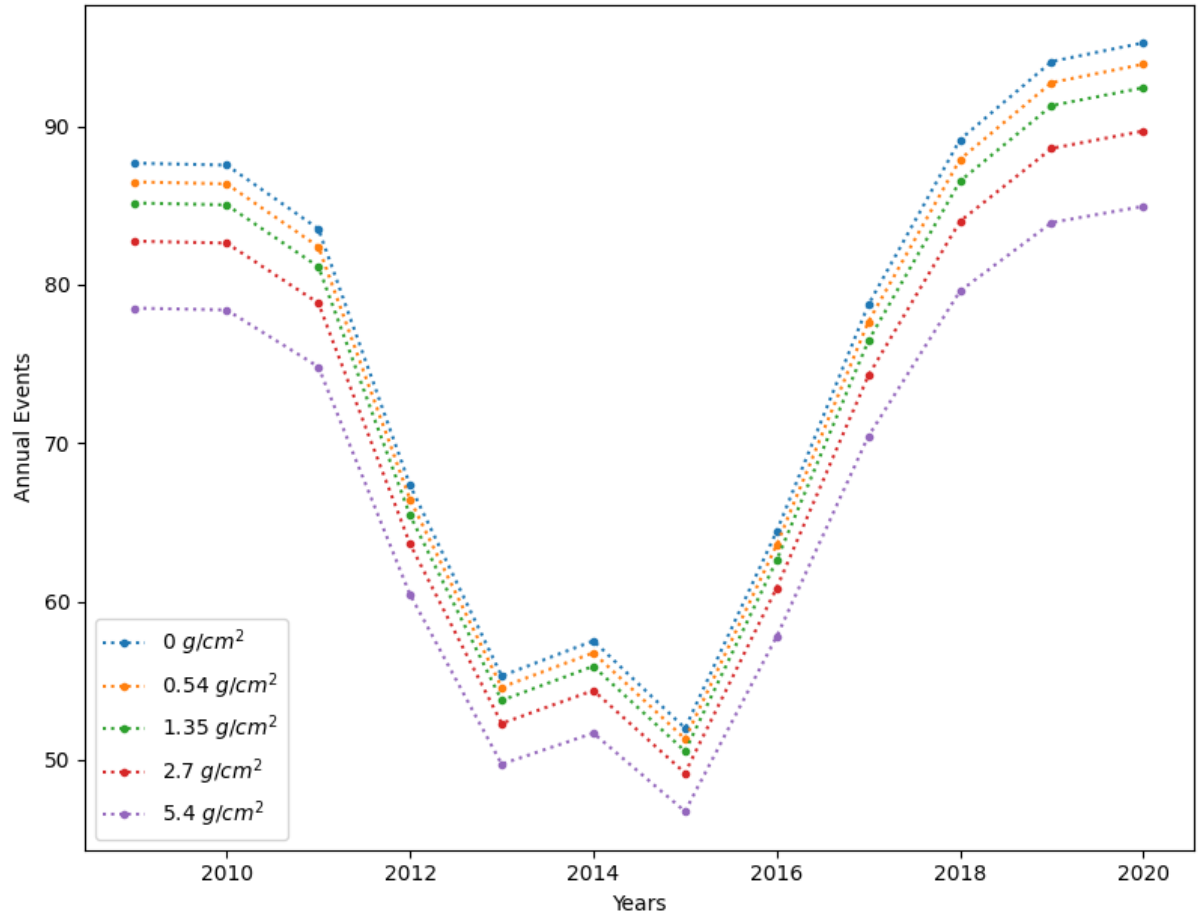


# Annual events on SEU Monitor during Solar Cycle 24

## Orbit – Proton Contribution

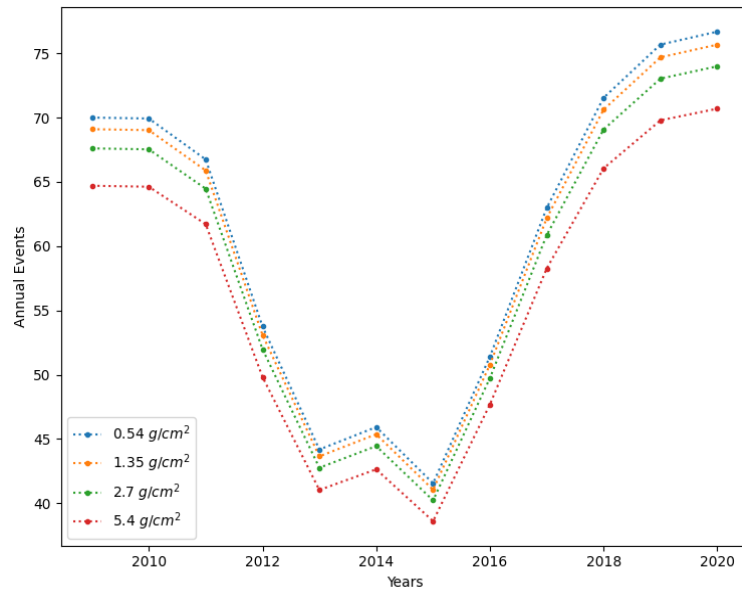


## Surface – Proton Contribution

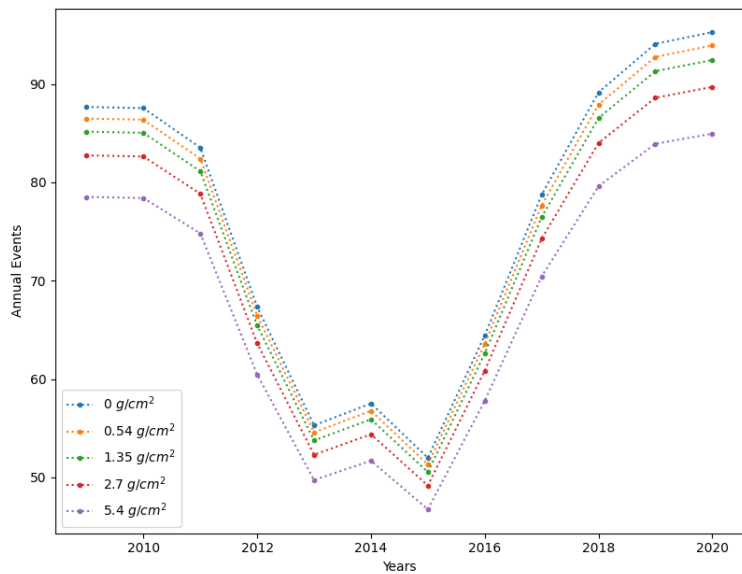


# Annual events on SEU Monitor during Solar Cycle 24

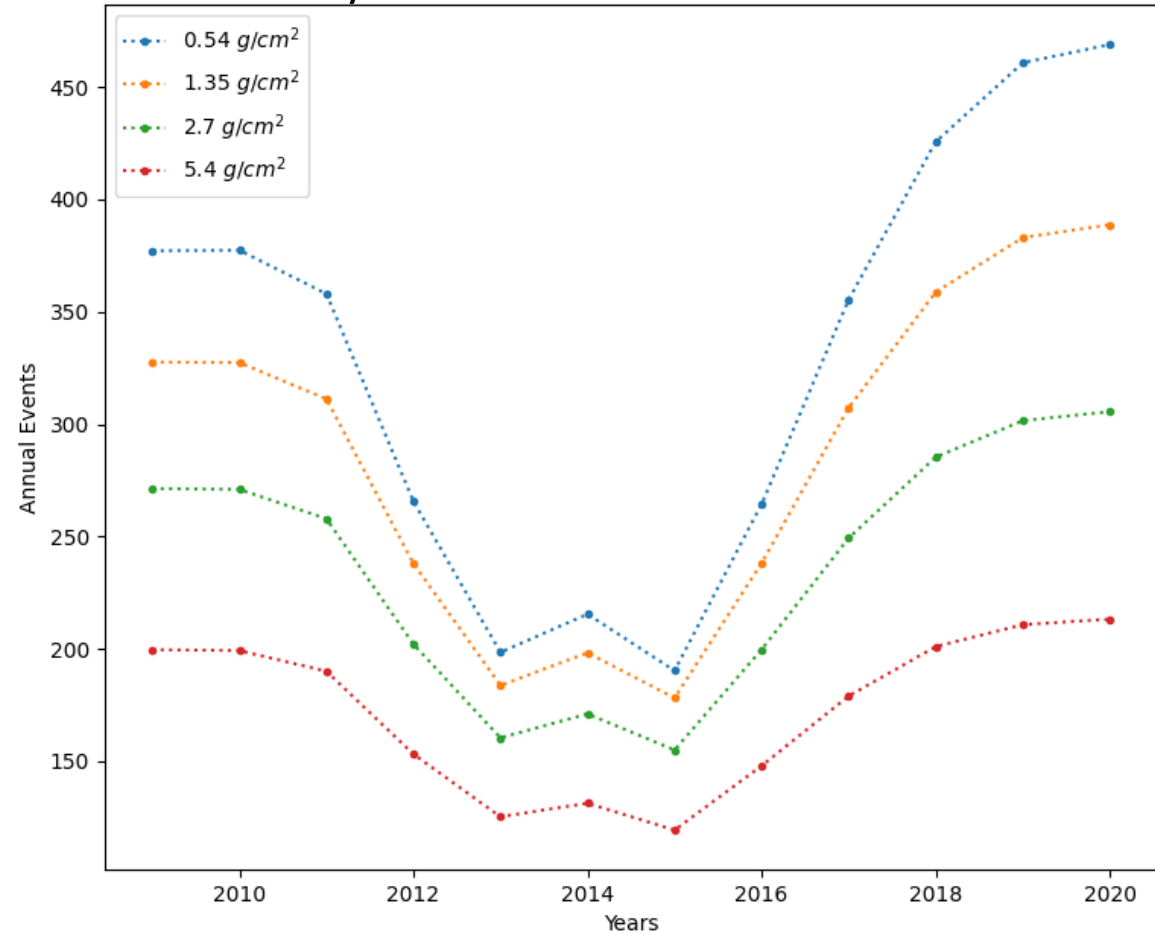
## Orbit – Proton Contribution



## Surface – Proton Contribution



## Orbit - Heavy Ions Total contribution



# Annual events on possible SRAM-based Monitors

		Number of Errors Detected at Orbit							
		Shielding: 0.54 g/cm <sup>2</sup>		Shielding: 1.35 g/cm <sup>2</sup>		Shielding: 2.70 g/cm <sup>2</sup>		Shielding: 5.40 g/cm <sup>2</sup>	
Component Name	Year	Z=1	HI Total	Z=1	HI Total	Z=1	HI Total	Z=1	HI Total
SEU Monitor	2009	70,00	377,15	69,10	327,59	67,61	271,32	64,70	199,58
	2014	45,93	215,43	45,37	198,23	44,45	171,02	42,64	131,26
BS62c	2009	16,41	177,92	16,20	151,37	15,84	122,51	15,16	87,50
	2014	10,82	95,53	10,68	87,27	10,46	74,04	10,03	55,39
IS62	2009	0,32	4,89	0,31	3,96	0,31	3,08	0,29	2,10
	2014	0,21	2,49	0,21	2,24	0,20	1,84	0,20	1,32

		Number of Errors Detected at the Surface (Z=1)				
Component Name	Year	Shielding: 0 g/cm <sup>2</sup>	Shielding: 0.54 g/cm <sup>2</sup>	Shielding: 1.35 g/cm <sup>2</sup>	Shielding: 2.70 g/cm <sup>2</sup>	Shielding: 5.40 g/cm <sup>2</sup>
SEU Monitor	2009	87,68	86,49	85,16	82,75	78,52
	2014	57,52	56,77	55,91	54,39	51,69
BS62c	2009	20,18	19,93	19,66	19,13	18,19
	2014	13,27	13,12	12,94	12,61	12,01
IS62	2009	0,38	0,37	0,37	0,36	0,34
	2014	0,25	0,25	0,25	0,24	0,23

Thank you for  
your attention

